

**Search Notes**

Application/Control No.

10/828,262

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

HATA ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	735 - 737, 706, 707, 711 & 276	8/4/2005	C.C.
257	780 & 781	8/4/2005	C.C.
257	783 & 772	8/4/2005	C.C.
257	787 & 713	8/4/2005	C.C.
257	775 & 341	8/4/2005	C.C.
257	796 & 690	8/4/2005	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
as same	as above	8/4/2005	C.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	8/4/2005	C.C.
Consulted with S. Clark 257/735 - 737, 706, 707, 711, 276, 780, 781, 783, 772 & 787word: source, gate, lead, beam, heat sink	4/12/2005	C.C.
Consulted with J. Jackson 257/713, 775, 341, 796	4/12/2005	C.C.
Consulted with A. Wilson	8/4/2005	C.C.